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PATENTS
MIC-20

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
PATENT APPLICATION

Applicant : Pary Baluswamy et al.

Application No.:

Filed : Herewith

For : PATTERN MASK WITH FEATURES TO
MINIMIZE THE EFFECT OF ABERRATIONS

New York, New York 10020
March 1, 2002

Hon. Commissioner for Patents
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to 37 C.F.R. §§ 1.56 and 1.97, applicants
hereby make the following patents and publications of record
in the above-identified patent application:

Wald et al. U.S. Patent 5,932,491 (August 3, 1999)
Pierrat et al. U.S. Patent 6,120,952
(September 19, 2000)
Stanton et al. U.S. Patent 6,144,109 (November 7,
2000)
Stanton U.S. Patent 6,214,497 (April 10, 2001)
Futrell et al. U.S. Patent 6,238,824 (May 29,
2001)
Stanton et al. U.S. Patent 6,242,816 (June 5,
2001)
Futrell et al. U.S. Patent 6,245,468 (June 12,
2001)
Stanton et al. U.S. Patent 6,258,489 (July 10,
2001)
Pierrat et al. U.S. Patent 6,284,419 (September 4,
2001)
Pierrat et al. U.S. Patent 6,319,644 (November 20,
2001)
Pierrat et al. U.S. Patent Application Publication
No. 2001/0002304A1 (May 31, 2001)

Futrell et al. U.S. Patent Application Publication
No. 2001/0023043A1 (September 20, 2001)
Pierrat et al. U.S. Patent Application Publication
No. 2001/0023045A1 (September 20, 2001)
Baggenstoss U.S. Patent Application Publication
No. 2001/0033979A1 (October 25, 2001)

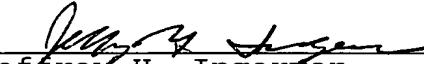
Peterson, J.S., "Analytical Description of Anti-scattering and Scattering Bar Assist Features," Proceedings of SPIE: Optical Microlithography XIII, vol. 4000, pp. 77-89 (March 1-3, 2000)

Copies of the aforementioned patents and publications, which are listed on the accompanying Form PTO-1449 (submitted in duplicate), are enclosed herewith.

It is respectfully requested that these patents and publications be (1) fully considered by the Patent and Trademark Office during examination of this application; and (2) printed on any patent which may issue on this application. Applicants request that a copy of Form PTO-1449, as considered and initialled by the Examiner, be returned with the next communication.

An early and favorable action is respectfully requested.

Respectfully submitted,



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| FORM PTO-1449 | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT | ATTY. DOCKET NO. MIC-20 | APPLN. NO. S. PTO 0073 |
| | | APPLICANT Pary Baluswamy et al. | FILING DATE Herewith |
| | | GROUP ART 10/01/02 | |

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|------------------|-----------------|---------|----------------|-------|----------|----------------------------|
| | 5,932,491 | 8/1999 | Wald et al. | 438 | 734 | |
| | 6,120,952 | 9/2000 | Pierrat et al. | 430 | 30 | |
| | 6,144,109 | 11/2000 | Stanton et al. | 257 | 797 | |
| | 6,214,497 | 4/2001 | Stanton | 430 | 5 | |
| | 6,238,824 | 5/2001 | Futrell et al. | 430 | 5 | |
| | 6,242,816 | 6/2001 | Stanton et al. | 257 | 797 | |
| | 6,245,468 | 7/2001 | Futrell et al. | 430 | 5 | |
| | 6,258,489 | 7/2001 | Stanton et al. | 430 | 5 | |
| | 6,284,419 | 9/2001 | Pierrat et al. | 430 | 30 | |
| | 6,319,644 | 11/2001 | Pierrat et al. | 430 | 30 | |
| | 2001/0002304A1 | 5/2001 | Pierrat et al. | 430 | 30 | |
| | 2001/0023043A1 | 9/2001 | Futrell et al. | 430 | 5 | |
| | 2001/0023045A1 | 9/2001 | Pierrat et al. | 430 | 30 | |
| | 2001/0033979A1 | 10/2001 | Baggenstoss | 430 | 5 | |
| | | | | | | |

FOREIGN PATENT DOCUMENTS

| EXAMINER INITIAL | DOCUMENT NUMBER | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION | |
|------------------|-----------------|------|---------|-------|----------|-------------|----|
| | | | | | | YES | NO |
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| EXAMINER INITIAL |  |
| | Peterson, J.S., "Analytical Description of Anti-scattering and Scattering Bar Assist Features," Proceedings of SPIE: Optical Microlithography XIII, vol. 4000, pp. 77-89 (March 1-3, 2000) |
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not conformance and not considered. Include copy of this form with next communication to applicant.